

Notice of References Cited

Application/Control No.

10/821,608

Applicant(s)/Patent Under
Reexamination
AGRAWAL ET AL.

Examiner

BACKHEAN TIV

Art Unit

2451

Page 1 of 6

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,576,951 A	05-1971	Uchida et al.	379/249
*	B	US-5,852,657 A	12-1998	Malik et al.	379/93.25
*	C	US-6,047,327 A	04-2000	Tso et al.	709/232
*	D	US-6,097,793 A	08-2000	Jandel, Magnus	379/93.23
*	E	US-6,259,471 B1	07-2001	Peters et al.	348/14.12
*	F	US-2001/0048738 A1	12-2001	BANIAK et al.	379/201.02
*	G	US-2002/0026500 A1	02-2002	Kanefsky et al.	709/219
*	H	US-6,400,958 B1	06-2002	Isomursu et al.	455/466
*	I	US-2002/0073149 A1	06-2002	Young, Christopher Tyler	709/204
*	J	US-2002/0137507 A1	09-2002	Winkler, Yair	455/426
*	K	US-6,456,854 B1	09-2002	Chern et al.	455/457
*	L	US-2002/0177454 A1	11-2002	Karri et al.	455/466
*	M	US-6,507,643 B1	01-2003	Groner, Gabriel F.	379/88.14

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/821,608

Applicant(s)/Patent Under
Reexamination
AGRAWAL ET AL.

Examiner

BACKHEAN TIV

Art Unit

2451

Page 2 of 6

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0026432 A1	02-2003	Woodward, Ernest E.	380/278
*	B	US-2003/0040327 A1	02-2003	Park, Yong-Kook	455/466
*	C	US-2003/0087648 A1	05-2003	Mezhvinsky et al.	455/456
*	D	US-2003/0091016 A1	05-2003	Ko et al.	370/338
*	E	US-2003/0100322 A1	05-2003	Jeon, Byung-Su	455/466
*	F	US-2003/0109247 A1	06-2003	Lindgren et al.	455/412
*	G	US-2003/0103607 A1	06-2003	Feakes, Kieren	379/88.17
*	H	US-2003/0182242 A1	09-2003	Scott et al.	705/65
*	I	US-2003/0191816 A1	10-2003	Landress et al.	709/219
*	J	US-2003/0191709 A1	10-2003	Elston et al.	705/40
*	K	US-2003/0217159 A1	11-2003	Schramm-Apple et al.	709/228
*	L	US-2003/0220835 A1	11-2003	Barnes, Melvin L. JR.	705/14
*	M	US-2004/0039781 A1	02-2004	LaVallee et al.	709/205

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited

Application/Control No.

10/821,608

Applicant(s)/Patent Under
Reexamination
AGRAWAL ET AL.

Examiner

BACKHEAN TIV

Art Unit

2451

Page 3 of 6

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0073691 A1	04-2004	Sun, Chen	709/230
*	B	US-2004/0087326 A1	05-2004	Dunko et al.	455/517
*	C	US-2004/0139163 A1	07-2004	Adams et al.	709/206
*	D	US-2004/0132431 A1	07-2004	Vandermeijden et al.	455/412.2
*	E	US-2004/0148351 A1	07-2004	Cotte, Pierre-Alain	709/205
*	F	US-2004/0143667 A1	07-2004	Jerome, Jason	709/228
*	G	US-2004/0138943 A1	07-2004	Silvermail, Brian	705/010
*	H	US-6,771,975 B1	08-2004	Shin, Hyun-jung	455/466
*	I	US-2004/0193691 A1	09-2004	Chang, William I.	709/206
*	J	US-2004/0176067 A1	09-2004	Lakhani et al.	455/406
*	K	US-2004/0186883 A1	09-2004	Nyman et al.	709/203
*	L	US-2004/0224723 A1	11-2004	Farcașiu, Alexandru M.	455/557
*	M	US-2004/0229656 A1	11-2004	Takahashi et al.	455/566

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No. 10/821,608	Applicant(s)/Patent Under Reexamination AGRAWAL ET AL.	
		Examiner BACKHEAN TIV	Art Unit 2451	Page 4 of 6

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0015443 A1	01-2005	Levine et al.	709/204
*	B	US-2005/0031106 A1	02-2005	Henderson, Samuel	379/142.17
*	C	US-2005/0144251 A1	06-2005	Slate, Michael L.	709/215
*	D	US-2005/0137984 A1	06-2005	Nguyen et al.	705/051
*	E	US-2005/0138193 A1	06-2005	Encarnacion et al.	709/230
*	F	US-6,907,239 B1	06-2005	Sivula, Timo E	455/406
*	G	US-2005/0160001 A1	07-2005	Lapre et al.	705/014
*	H	US-2005/0227678 A1	10-2005	Agrawal et al.	455/414.3
*	I	US-2005/0229118 A1	10-2005	Chiu et al.	715/864
*	J	US-2005/0246193 A1	11-2005	Roever et al.	705/001
*	K	US-6,965,770 B2	11-2005	Walsh et al.	455/426.1
*	L	US-2005/0266835 A1	12-2005	Agrawal et al.	455/414.3
*	M	US-2006/0026534 A1	02-2006	Ruthfield et al.	715/854

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/821,608		Applicant(s)/Patent Under Reexamination AGRAWAL ET AL.	
	Examiner BACKHEAN TIV		Art Unit 2451	Page 5 of 6

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,020,685 B1	03-2006	Chen et al.	709/204
*	B	US-7,043,238 B2	05-2006	Ahn et al.	455/432.1
*	C	US-2006/0095502 A1	05-2006	Lewis et al.	709/203
*	D	US-2006/0116167 A1	06-2006	Raviv et al.	455/558
*	E	US-2006/0168095 A1	07-2006	Sharma et al.	709/217
*	F	US-2006/0168004 A1	07-2006	Choe et al.	709/206
*	G	US-2006/0291455 A1	12-2006	Katz et al.	370/355
*	H	US-2007/0083408 A1	04-2007	ALTBERG et al.	705/007
*	I	US-7,200,680 B2	04-2007	Evans et al.	709/246
*	J	US-7,206,806 B2	04-2007	Pineau, Richard A.	709/203
*	K	US-7,216,109 B1	05-2007	Donner, Irah H.	705/64
*	L	US-7,272,637 B1	09-2007	Himmelstein, Richard B.	709/217
*	M	US-7,277,733 B2	10-2007	Ko et al.	455/566

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited	Application/Control No. 10/821,608		Applicant(s)/Patent Under Reexamination AGRAWAL ET AL.	
	Examiner BACKHEAN TIV		Art Unit 2451	Page 6 of 6

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,317,908 B1	01-2008	Eason, Wendy	455/413
*	B	US-7,343,168 B2	03-2008	Valloppillil, Vinod	455/466
*	C	US-7,370,077 B2	05-2008	Pradhan et al.	709/204
*	D	US-7,369,868 B2	05-2008	Dunko et al.	455/517
*	E	US-2008/0153468 A1	06-2008	REILLY, Paul Jefferson	455/414.2
*	F	US-2008/0141128 A1	06-2008	Takahashi et al.	715/700
*	G	US-2008/0212944 A1	09-2008	Khedouri et al.	386/124
*	H	US-2009/0053995 A1	02-2009	MOORE, III, Roscoe M.	455/13.1
*	I	US-7,519,720 B2	04-2009	Fishman et al.	709/230
*	J	US-2009/0191904 A1	07-2009	Hronek et al.	455/466
*	K	US-7,584,225 B2	09-2009	Jiang et al.	1/1
*	L	US-7,590,681 B1	09-2009	Chang et al.	709/203
*	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.